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M Karam, W Fikry, H Haddara, H Ragai - Circuits and Systems, 2001. ISCAS 2001. The 2001 IEEE ..., 2001 ieeexplore.ieee.org

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13	BRS	L13	322	(circuit adj degradation)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 17:24
14	BRS	L14	5	(circuit adj degradation) and (first adj set) and (second adj set)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 17:25